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PATENT & TRADEMARK OFFICE

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In Re Patent Application Of:	Babchin et al.	Our File No:	51-15 US CIP/PCT
Application No:	09/929,092	Group Art Unit:	1753
Filed:	August 15, 2001	Examiner:	Mayekar, Kishor
Title:	Dielectric Breakdown Chemical Reactor for Liquids		

April 2, 2004

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450, U.S.A.

Declaration Under 37 CFR 1.132

Sir:

We, Alexander Joseph Babchin, Jian-Yang Yuan, Ezra Eddy Isaacs, Haibo Huang, Ross Sam Chow, Richard Anthony McFarlane and Dmytro Vassily Prudkyy, the applicants of the above-identified patent application and the joint inventors of the subject matter described and claimed therein, depose and state:

1. The term "dielectric breakdown" is well known in the field of the invention and has a specific meaning that will be readily understood by one of ordinary skill in the art.

2. "Dielectric breakdown" occurs when a critical electric field is exceeded, and branched conduction paths grow at microsecond speeds through a sample. A dielectric breakdown event is an abrupt discharge, or arc, that occurs as a result of a failure of the sample to behave as an insulator under the influence of the critical electric field.

3. In the case of a liquid sample, intense ionization occurring at the branch tips of the conduction paths results in plasma formation within the liquid sample.

4. Attached to this our Declaration and marked as Exhibit A is a portion of the National Institute of Standards and Technology website, containing information relating to dielectric breakdown as presented at point 2, above.

5. Attached to this our Declaration and marked as Exhibit B is a document retrieved from the Compliance West USA website (http://www.compwest.com/our_products/pdf/arc_detection.pdf). Compliance West USA manufactures product safety test equipment for use in the field of the invention and the information presented on the website is believed to be representative of the knowledge available to one of ordinary skill in the art. Exhibit B contains additional information relating to dielectric breakdown as presented at point 2, above.

6. We acknowledge that willful false statements and the like are punishable by fine or imprisonment, or both (18 U.S.C. 1001) and may jeopardize the validity of the application or any patent issuing thereon.

7. All statements made of declarant's own knowledge are true and all statements made on information and belief are believed to be true.

Signed,

A Babchin

Alexander Joseph Babchin

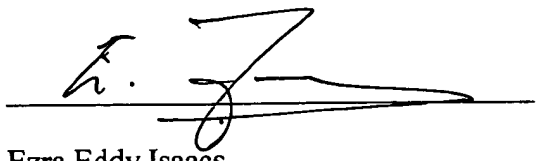
April 02/2004

Date

Jian-Yang Yuan

April 2nd, 2004

Date



Ezra Eddy Isaacs

April 05, 2004

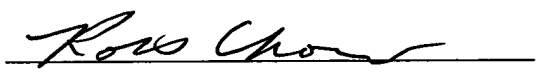
Date



Haibo Huang

April 2/04

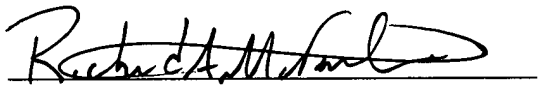
Date



Ross Sam Chow

2 April 04

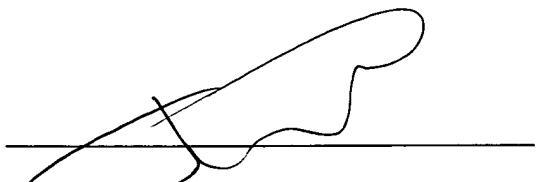
Date



Richard Anthony McFarlane

Apr 2/2004

Date



Dmytro Vassily Prudkyy

Apr 05/2004

Date